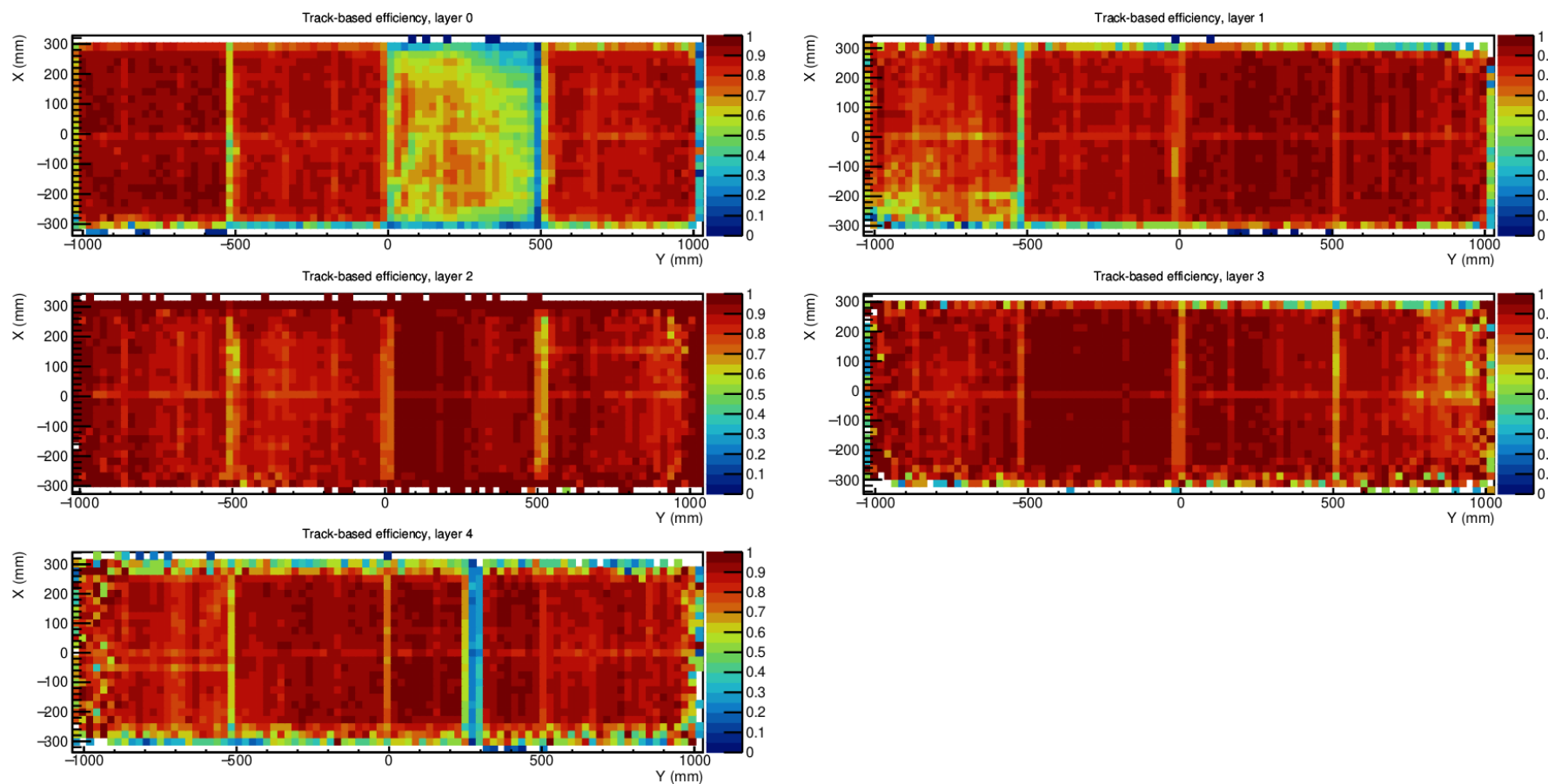
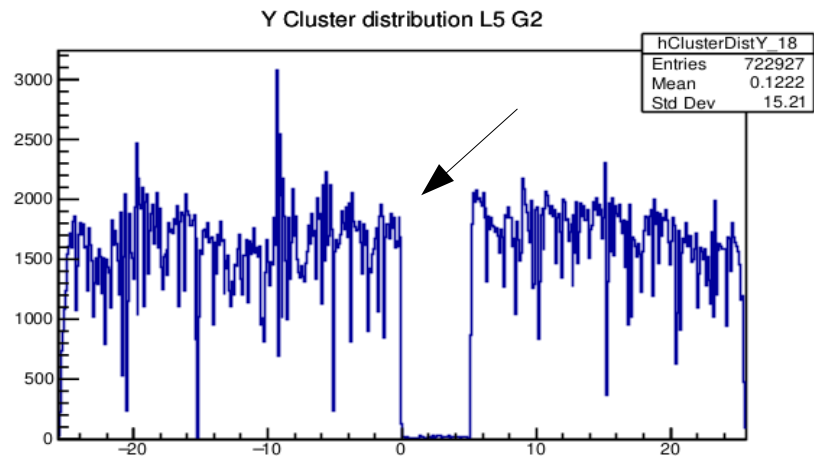
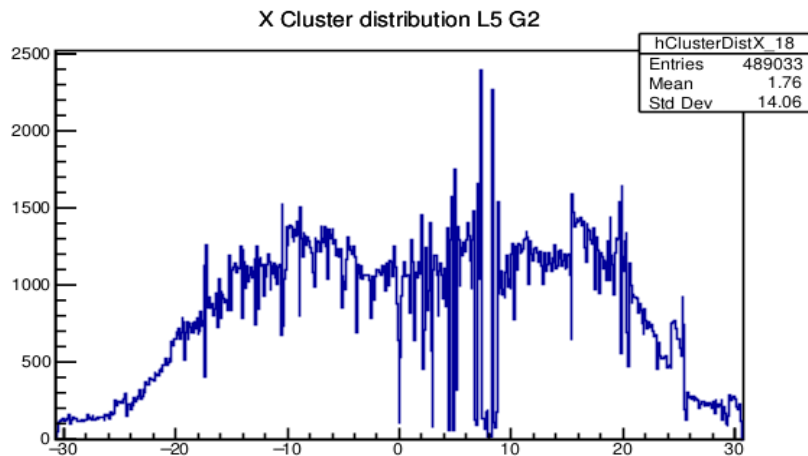


Low efficiency region on the 3rd module of Layer5

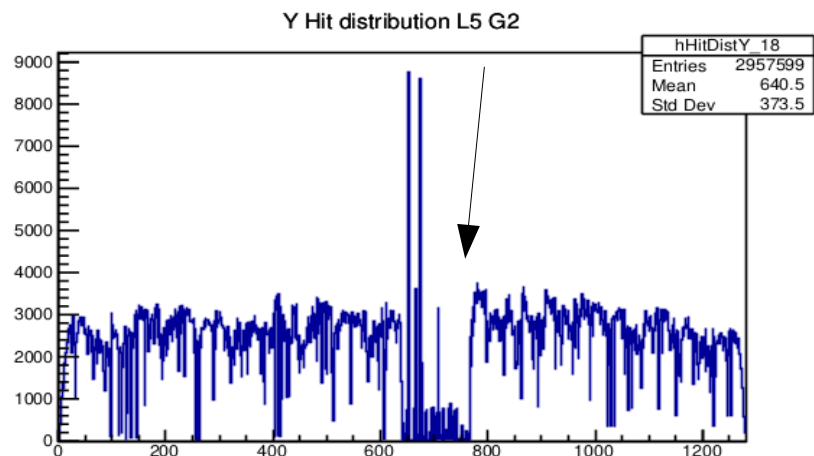
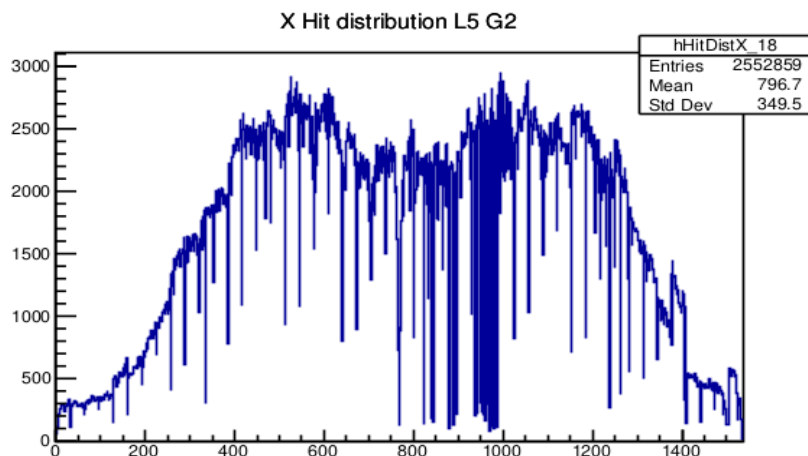
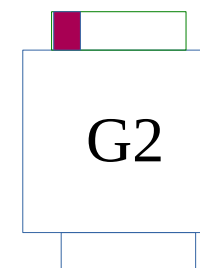


Cluster and hit distributions for 3rd module of L5



Left back plane

y →



G2 → Third module

Updates:

What we did:

- Replaced analog cables (one white and two blue) connected to the back plane => no change in results
- Replaced APV25 cards => no change in results

What we planned to test next:

- The patch panel that splits 3 short analog cables into 4 long cables
- The data with no APV25 connected to make sure we are looking at the right APV25
- Replace the back plane

Daq stability during HV scan

- Encountered occasional MPD errors for the MPD7 attached to the second crate => Need to test/replace the first HDMI cable connected to this MPD

For troubleshooting we unplugged and plugged back this cable to get this MPD working.

- TI in sbsvme25 (roccrate1) is no longer responding through VME => Return after a power cycle but need to replace it in future

Cluster finding in root gui

- Find cluster on X and Y by checking if there are adjacent fired strips. If there are at least two fired strips close to each other, this will be considered as cluster
- For each cluster found in step one, add all the strip ADCs,. this will be considered as the cluster ADC ->> accumulated charge
- Sort the X and Y cluster charge value calculated from step 2.
- Match the X and Y. It will consider Highest ADC on X corresponding the highest on Y , and so on